NSN 6650-01-250-1243

Diffraction Pat Measuring Device - Page 1 of 1



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General Description:

C/o densitometer and recorder; determins rate of d spacings from electron and x-ray diffraction patterns; automatically produces permanent expanded chart record of variations in film density along selected track; chart may be read to line spacing of between 0.05 and 0.10 mm for d value determinations; outer support ring has 360 degrees protractor scale; bench sz 44 x 16 in.

Life:
Life:

N/a

Unit Of Measure:

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Demilitarization:

Yes - demil/mli